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APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10619341	07/14/2003	360	324.120	2653	HEINZ, A 8C72
<b>**APPLICANTS:</b> Naoya Hasegawa; Eiji Umetsu;					
<b>**CONTINUING DATA VERIFIED:</b>					
<b>** FOREIGN APPLICATIONS VERIFIED:</b> JAPAN 2002-206544 07/16/2002					
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Foreign priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no				ATTORNEY DOCKET NO	
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Verified and Acknowledged Examiners's initials <i>JA</i>					
<b>TITLE :</b> Magnetic sensor with second antiferromagnetic layer having smaller depth in height direction than free layer and manufacturing method thereof					
U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)					